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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/605,214	09/16/2003	Chih-Hung Su	9789-US-PA	2213

31561 7590 03/06/2006

JIANQ CHYUN INTELLECTUAL PROPERTY OFFICE
7 FLOOR-1, NO. 100
ROOSEVELT ROAD, SECTION 2
TAIPEI, 100
TAIWAN

EXAMINER

GARCIA, JOANNIE A

ART UNIT	PAPER NUMBER
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2823

DATE MAILED: 03/06/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	Application No. 10/605,214	Applicant(s) SU ET AL.	
	Examiner Joannie A. Garcia	Art Unit 2823	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --
Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 16 December 2005.
- 2a) ☒ This action is **FINAL**. 2b) ☐ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1,2,5-9,13 and 14 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1,2,8 and 9 is/are rejected.
- 7) ☒ Claim(s) 5-7,13 and 14 is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☒ All b) ☐ Some * c) ☐ None of:
1. ☒ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. _____.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- * See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)
Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____ |

The text of those sections of Title 35, U.S. Code not included in this action can be found in a prior Office action.

Claims 1 and 2 are rejected under 35 U.S.C. 102(e) as being anticipated by Lee et al (US 2002/0074548 A1).

The rejection is maintained as stated in the Office Action mailed 09-19-05, and as stated below.

Applicant argues that Lee et al does not teach forming a passivation layer on the substrate to cover the organic light emitting diode unit. However, Lee et al discloses providing a substrate 40 having an organic light emitting diode unit thereon, as disclosed in Figure 4A, and in Paragraphs 0001, 002, and 0025, and forming a passivation layer 42 on the substrate 40 to cover the organic light emitting diode unit, as disclosed in Figure 4B, and in Paragraph 0026, therefore achieving formation on a substrate of a covering passivation layer of an organic light emitting diode unit.

Applicant argues that Lee et al does not teach performing a surface treatment on the passivation layer, and that a surface treatment on a layer may merely result in an alteration of properties of the surface of the layer, whereas forming a doped region under the layer requires dopants to penetrate through the entire layer to form a doped region there under. However, Lee et al discloses providing an ion beam such as ion implantation, to perform a surface treatment on the passivation layer 42, as disclosed in Figure 4C, and in Paragraph 0027, therefore achieving formation of a surface treated passivation layer. Furthermore, Lee et al discloses penetrating through the entire passivation layer 42 to form a doped region (Paragraph 0027), therefore,

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achieving a surface treatment on layer 42 resulting in an alteration of properties of the surface of the layer.

Lee et al discloses providing a substrate 40 having an organic light emitting diode unit thereon (Figure 4a, and Paragraphs 0001, 0002, and 0025), forming a passivation layer 42 on the substrate to cover the organic light emitting diode unit (Figure 4B, and Paragraph 0026), wherein the passivation layer is formed of either silicon nitride or silicon oxide (Paragraph 0026), and providing an ion beam such as ion implantation, to perform surface treatment on the passivation layer (Figure 4C, and Paragraph 0027).

Claims 8 and 9 are rejected under 35 U.S.C. 102(b) as being anticipated by Sasaki (U.S. Patent 4,404,733).

The rejection is maintained as stated in the Office Action mailed 09-19-05, and as stated below.

Applicant argues that Sasaki does not teach providing an ion beam to perform surface treatment on the passivation layer for at least the same reasons discussed above. However, Sasaki discloses providing an ion beam such as ion implantation, to perform a surface treatment on the passivation layer 13, as disclosed in Figure 2b, and in Column 3, lines 20-27, therefore achieving formation of a surface treated passivation layer. Furthermore, Sasaki discloses penetrating through the entire passivation layer 13 to form a doped region (Column 3, lines 20-27), therefore, achieving a surface treatment on layer 13 resulting in an alteration of properties of the surface of the layer.

Applicant argues that Sasaki does not teach forming a plastic layer on the passivation layer. However, Sasaki discloses forming a plastic layer 25 on the passivation layer 13, as disclosed in Figure 2h, and in Column 1, lines 17-23, and Column 4, lines 45-55. Sasaki discloses that the plastic layer 25 is made of silicon oxide, as disclosed in Column 2, lines 40-47, and in Column 3, line 27-35, and that the plastic layer 25 is formed on the passivation layer 13, as shown in Figure 2h.

Sasaki discloses forming a silicon oxide passivation layer 13 to cover an electronic device formed on substrate 11 (Figure 2a, and Column 3, lines 10-19), providing an ion beam such as ion implantation to perform surface treatment on the passivation layer (Figure 2b, and Column 3, lines 20-27), and forming a plastic layer 25 on the passivation layer (Figure 2h, Column 1, lines 17-23, and Column 4, lines 45-55).

Claims 5-7, 13, and 14, are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire **THREE MONTHS** from the mailing date of this action. In the event a first reply is filed within **TWO MONTHS** of the mailing date of this final action and the advisory action is not mailed until after the end of the **THREE-MONTH** shortened statutory period, then the shortened statutory period

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will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Joannie García whose telephone number is (571) 272-1861. The examiner can normally be reached on Monday through Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew Smith, can be reached on (571) 272-1907. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

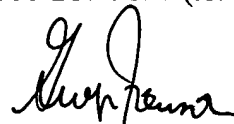


JAG

February 28, 2006

GFourson

Primary Examiner



George Fourson

Primary Examiner

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